

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/588,065 SUGIURA ET AL.	
		Examiner	Art Unit	Page 1 of 1 CHAU NGUYEN 2176

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0053468	03-2006	Sudoh et al.	725/135
*	B	US-2003/0016947	01-2003	Ishii, Yoshiaki	386/52
*	C	US-2004/0075678	04-2004	Kazui et al.	345/723
*	D	US-2003/0122862	07-2003	Takaku et al.	345/723
*	E	US-2003/0146915	08-2003	Brook et al.	345/473
*	F	US-2003/0191816	10-2003	Landress et al.	709/219
*	G	US-2005/0084232	04-2005	Herberger et al.	386/004
*	H	US-7,466,349	12-2008	Iijima, Jun	348/231.99
*	I	US-7,149,961	12-2006	Harville et al.	715/202
J	US-				
K	US-				
L	US-				
M	US-				

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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